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# Jameco Part Number 301268

# SN54LS139A, SN54S139, SN74LS139A, SN74S139A DUAL 2-LINE TO 4-LINE DECODERS/DEMULTIPLEXERS

#### SDLS013

- Designed Specifically for High-Speed: Memory Decoders
  Data Transmission Systems
- Two Fully Independent 2- to 4-Line Decoders/Demultiplexers
- Schottky Clamped for High Performance

#### description

These Schottky-clamped TTL MSI circuits are designed to be used in high-performance memory-decoding or data-routing applications requiring very short propagation delay times. In high-performance memory systems, these decoders can be used to minimize the effects of system decoding. When employed with highspeed memories utilizing a fast-enable circuit, the delay times of these decoders and the enable time of the memory are usually less than the typical access time of the memory. This means that the effective system delay introduced by the Schottky-clamped system decoder is negligible.

The circuit comprises two individual two-line to four-line decoders in a single package. The active-low enable input can be used as a data line in demultiplexing applications.

All of these decoders/demultiplexers feature fully buffered inputs, each of which represents only one normalized load to its driving circuit. All inputs are clamped with high-performance Schottky diodes to suppress line-ringing and to simplify system design. The SN54LS139A and SN54S139 are characterized for operation range of -55 °C to 125 °C. The SN74LS139A and SN74S139A are characterized for operation from 0 °C to 70 °C.

INP	OUTPUTS					
ENABLE	SELECT			001	FUIS	
G	6	Α	YO	Υ1	Υ2	Y3
н	Х	х	н	н	н	Η
L	L	L	L	н	н	н
L	L	Н	н	L	н	н
L	н	L	н	н	L	н
L	н	н	н	н	н	L

H = high level, L = low level, X = irrelevant

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications par the terms of Texas instruments standard warranty. Production processing does not necessarily include testing of all parameters. DECEMBER 1972 - REVISED MARCH 1988

SN54LS139A, SN54S139 J OR W PACKAGE
SN74LS139A, SN74S139A D OR N PACKAGE
(TOP VIEW)

_	<u> </u>
1 🖸 🚺 1	
1 A 🗌 2	15 🗌 2 G
18 🛛 3	14 🗌 2A
1Y0 🛛 4	13 🗍 2B
1Y1 🗖 5	12 270
1Y2 🚺 6	11 🗍 2Y1
1Y3 🛛 7	10 🗋 2Y2
	<u>9</u> 2Y3

#### SN54LS139A, SN54S139 ... FK PACKAGE (TOP VIEW)



NC-No internal connection

#### logic symbols (alternatives)<sup>†</sup>



<sup>†</sup>These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, N, and W packages.

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# SN54LS139A, SN54S139, SN74LS139A, SN74S139A DUAL 2-LINE TO 4-LINE DECODERS/DEMULTIPLEXERS

logic diagram (positive logic)



Pin numbers shown are for D, J, N, and W packages.

## schematics of inputs and outputs



## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (See Note 1)	<b>7</b> V
Input voltage: 'LS139A	
54\$139, 74\$139A	5.5 V
Operating free-air temperature range: SN54LS139A, SN54S139	-55°C to 125°C
SN74LS139A, SN74S139A	. 0° C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



# SN54LS139A, SN74LS139A **DUAL 2-LINE TO 4-LINE DECODERS/DEMULTIPLEXERS**

### recommended operating conditions

		SN	54LS13	9A	SN	174LS13	19A	LIBUT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage	·		0.7			0.8	v
юн	High-level output current			-0.4			-0.4	mA
IOL	Low-level output current			4				mA
TA	Operating free-air temperature	- 55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS <sup>†</sup>		SN54LS139A			SN	1			
				MIN	TYP <sup>‡</sup>	MAX	MIN	TYP <sup>‡</sup>	MAX	UNIT
VIK	$V_{CC} = MIN, \qquad I_{\parallel} = -18 \text{ mA}$					-1.5			- 1.5	V
V <sub>OH</sub>	V <sub>CC</sub> = MIN, IOH = ~0.4 mA	V <sub>IH</sub> = 2 V,	$V_{IL} = MAX,$	2.5	3.4		2.7	<b>3</b> .4		v
VOL	$V_{CC} = MIN,$	V <sub>IH</sub> = 2 V,	$I_{OL} = 4 \text{ mA}$	-	0.25	0.4		0.25	0.4	
¥0L	V <sub>IL</sub> = MAX		IOL = 8 mA					0.35	0.5	V
4	$V_{CC} = MAX,$	V <sub>1</sub> = 7 V				0.1			0.1	mA
Iн	$V_{CC} = MAX,$	VI = 2.7 V				20			20	μA
<u> </u>	$V_{CC} = MAX,$	VI = 0.4 V		_		-0.4			-0.4	mA
los	$V_{CC} = MAX$			- 20		- 100	- 20		- 100	mΑ
'cc	V <sub>CC</sub> = MAX,	Outputs enable	and open		6.8	11	· ·	6.8	11	mA

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

<sup>‡</sup>All typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25 °C$ .

<sup>§</sup>Not more than one output should be shorted at a time, and duration of the short circuit test should not exceed one second.

# switching characteristics, $V_{CC}$ = 5 V, $T_A$ = 25 °C (see Note 2)

PARAMETER <sup>¶</sup> FROM (INPUT)		TO (OUTPUT)	LEVELS OF DELAY	TEST CONDITIONS		SN54LS139A SN74LS139A								
	(001701)	OF DELAT		MIN	TYP	MAX								
tPLH			2			13	20	ns						
<sup>T</sup> PHL	Binary	Any	Any	Any	Any	Any	Anγ	Any	-			22	33	ns
<sup>t</sup> PLH	Select								3			18	29	ns
<sup>t</sup> PHL			3	$R_L = 2 k\Omega$ , $C_L = 15 pF$		25	38	ns						
t <b>p</b> LH	Enable	A 1917	2			16	24	ns						
t <b>P</b> HL	LINADIC	Αηγ	<b>Z</b>			21	32	ns						

TtPLH = propagation delay time, low-to-high-level output

tpHL = propagation delay time, high-to-low-level output NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



# SN54S139, SN74S139A DUAL 2-LINE TO 4-LINE DECODERS/DEMULTIPLIERS

#### recommended operating conditions SN54S139 SN74S139A UNIT NOM MIN NOM MIN MAX MAX VCC Supply voltage 4.5 5 5.5 4.75 5 5.25 ۷ ⊻н High-level input voltage 2 2 ٧ VIL Low-level input voltage 0.8 0.8 v і<u>он</u> High-level output current - 1 - 1 mA 20 mΑ Low-level output current 20 IQL ΤA -55 125 0 70 °C Operating free-air temperature

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS <sup>†</sup>					SN54S139 SN74S139A			
					MIN	TYP <sup>‡</sup>	MAX	1	
VIK	V <sub>CC</sub> = MIN,	lj = -18 mA	, <u></u> _				-1.2	V	
M	$V_{CC} = MIN,$	$V_{IH} = 2 V_{e}$	$V_{1L} = 0.8 V_{2}$	SN54S'	2.5	3.4		v	
∨он	IOH = -1 mA			SN745'	2.7	3.4		ľ	
VOL	V <sub>CC</sub> = MIN, I <sub>OL</sub> = 20 mA	V <sub>1H</sub> = 2 ∨,	V <sub>IL</sub> = 0.8 V,	-			0.5	v	
1	VCC = MAX,	VI = 5.5 V					1	mA	
lін .	$V_{CC} = MAX,$	V₁ = 2.7 V					50	μA	
ΙL	$V_{CC} = MAX,$	Vj = 0.5 V					- 2	mA	
los <sup>§</sup>	$V_{CC} = MAX$				-40		- 100	mA	
lcc	$V_{CC} = MAX,$	Outputs enable	ed and open			60	90	mΑ	

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

<sup>‡</sup>All typical values are at  $V_{CC} = 5 V$ ,  $T_A = 25 °C$ .

<sup>§</sup>Not more than one output should be shorted at a time, and duration of the short circuit test should not exceed one second.

# switching characteristics, $V_{CC} = 5 V$ , $T_A = 25 °C$ (see Note 2)

	FROM	TO		TEST CONDITIONS		SN54S139 SN74S139A		UNIT							
	(INPUT)	(OUTPUT)	OF DELAY		MIN	TYP	MAX								
tPLH		Any 2 Any 3 Any 2				5	7.5	ns							
<sup>t</sup> PHL	Binary		Αηγ	Anγ	Any	Any	Any	Any	<b>A</b>	2			6.5	10	ns
<sup>t</sup> PLH	Select								2		-	7	12	ns	
<sup>t</sup> PHL				- 3	$R_{L} = 280 \ \Omega, \qquad C_{L} = 15$	pr	8	12	ns						
tPLH	F-shia Aru		<b>A</b> =	<b>A</b> =	2			5	8	ns					
tPHL	Enable		2			6.5	10	ns							

 $f_{tpLH}$  = propagation delay time, low-to-high-level output

tpHL = propagation delay time, high-to-low-level output

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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